## **Registration (Fax Reply)**

To: ECPE e.V.

Att.: Ingrid Bollens, <a href="mailto:lngrid.bollens@ecpe.org">lngrid.bollens@ecpe.org</a>

Please **e-mail** a scanned copy of the completed form or

send a fax to: +49 (0)911 / 81 02 88 - 28

Register before 23 November 2011

#### Participation fee:

- O €350.–\* for industry
- 15 % discount for members of ZVEI ○ €260.–\* for universities/institutes
- O € 80.-\* for students/PhD (shortened workshop package)

The fee includes dinner, lunch, coffee/soft drinks and a CD with the workshop presentations. A printed version of the workshop handout is available on request (€ 42.--\*).

With the confirmation of registration you will receive the invoice. (\*plus VAT) In case of cancellation after 23 November 2011 or non-attendance 50 % of the participation fee are payable.

Three participants from each ECPE member company are free of charge. Allocation in sequence of registration.

#### Sender:

Title, given name, name

Company, department

Full address

Phone, fax

E-mail

Date, signature

## **Organisational information**

Organiser ECPE e.V. 90443 Nuremberg, Germany www.ecpe.org

Chairmen Prof. Eckhard Wolfgang, ECPE

Helmut Keller, ZVEI

Dr. Martin Rittner, Robert Bosch

Thomas Harder, ECPE

**Organisation** Ingrid Bollens, ECPE e.V.

+49 (0)911 / 81 02 88 – 10 ingrid.bollens@ecpe.org

Workshop venue Hilton Hotel Nürnberg

Valznerweiherstrasse 200 90480 Nuremberg, Germany

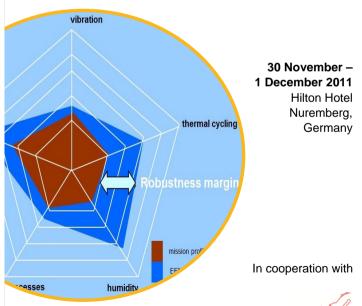


Further information (hotel list and maps) will be provided after registration.



## **ECPE Workshop**

# Robustness Validation in Power Electronics









## **ECPE Workshop**

## Robustness Validation in Power Electronics

30 November – 1 December 2011 Nuremberg, Germany

Members of SAE, ZVEI, AEC, and JSAE formed a joint task force to settle a **new Approach in Qualification** – the **Robustness Validation** process.

The new "test to fail" qualification approach (instead of a "test-to-pass"), is a paradigm shift from "Fit for Standard" to "Fit for Application". It generates knowledge on the relevant component failure mechanisms that may occur at the boundaries of the specification limits.

The first handbook was published in 2006. Since then 13 other documents were developed which cover semiconductor components, electric and electronic modules (ECUs) and systems. These documents are available from the ZVEI website <a href="https://www.zvei.org">www.zvei.org</a>

2008 a joint ZVEI-ECPE power electronics working group was formed which works on the knowledge matrix for power semiconductor modules. So far interconnects and substrates were studied. Recently work on adequate reliability tests was started.

The ECPE-ZVEI workshop on "Robustness validation in Power Electronics" is aiming for:

- Describing the status of the RV process
- Success stories (case studies)
- Describing challenges
- General exchange of experiences
- Collection of needs for action

The workshop is chaired by Prof. Eckhard Wolfgang (ECPE), Helmut Keller (ZVEI), Dr. Martin Rittner (Robert Bosch) and Thomas Harder (ECPE). All presentations and discussions will be in English.

## **Programme**

#### Wednesday, 30 November 2011

16:30	Start of Registration / Welcome reception
17:00	Welcome Address, Opening T. Harder, E. Wolfgang, ECPE e.V.
17:20	Robustness Validation – A Must for Power Devices W. Kanert, Infineon
17:50	Status Robustness Validation Process H. Keller, ZVEI
18:20	Robustness Validation: Design for Reliability J. Breibach, Robert Bosch
18:50	Discussion
19:30	Dinner at Hilton Hotel

#### Thursday, 1 December 2011

#### **Case studies**

8:30	<b>The Audace Project</b> P. Pougnet, Valeo
8:45	Electrical Overstress (EOS) Robustness of MOSFETs L. Lachèze, Presto Engineering - LaMips
9:00	Repetitive Clamping Applied to Smart Power Devices W. Kanert, Infineon
9:15	Case Study on Robustness Validation S. Pugliese, STMicroelectronics
9:30	Discussion

#### 10:10 Coffee Break

Lunch

#### **Requirements and Systems Engineering**

10:40	Mission Profile and Drive Train Topology R. Plikat, Volkswagen
11:10	Application Specific Mission Profile F. Weikelmann, Harman Automotive Division
11:30	Robustness Validation in Avionics B. Enser, Sanmina
11:45	Reliability Target's Setting and Follow up on Field Failure P. Rimmen, Danfoss Power Electronics
12:00	Discussion

### **Programme**

#### Thursday, 1 December 2011

Life Time and Reliability	
13:30	Total Reliability Approach vs Robustness Validation U. Scheuermann, Semikron
13:45	Virtual Testing of Robustness Based on Predictive Computer Simulation G. Wachutka, TU Munich
14:00	Predictive Reliability at Freescale P. Dupuy, Freescale
14:15	Modelling of End-of-Lifetime Based on Physics of Failure

4:30 Discussion	
-----------------	--

M. Abrate, Fiat CRF

#### 14:45 Coffee Break

#### Life Time and Reliability

15:15	Combinatorial Reliability Testing O. Wittler, Fraunhofer IZM
15:30	Lifetime Validation of Power Modules H. Voelkel, BMW
16:00	Discussion and Summary
16:30	End of Workshop